

### HM70P04-VB Datasheet

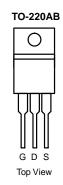
## P-Channel 40-V (D-S) MOSFET

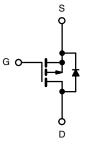
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	r <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)		
- 40	0.0041 at V <sub>GS</sub> = - 10 V	- 110	185 nC		

#### **FEATURES**

• Trench Power MOSFET







P-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 40	V
Gate-Source Voltage		V <sub>GS</sub>	± 20	
	T <sub>C</sub> = 25 °C		- 110 <sup>a</sup>	
Continuous Droin Current (T 175 °C)	T <sub>C</sub> = 70 °C		- 110 <sup>a</sup>	
Continuous Drain Current ( $T_J = 175 \ ^\circ C$ )	T <sub>A</sub> = 25 °C	I <sub>D</sub>	39 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		33 <sup>b, c</sup>	A
Pulsed Drain Current		I <sub>DM</sub>	240	A
Continuous Courses Drain Diada Current	T <sub>C</sub> = 25 °C		110	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	10 <sup>b, c</sup>	
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	75	
Single-Pulse Avalanche Energy	L = 0.1 IIIA	E <sub>AS</sub>	281	mJ
	T <sub>C</sub> = 25 °C		375	
Maximum Dawar Discinction	T <sub>C</sub> = 70 °C	P <sub>D</sub>	262	w
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	۲D	15 <sup>b, c</sup>	vv
	T <sub>A</sub> = 70 °C		10.5 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	
Soldering Recommendations (Peak Temperature		260		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	8	10	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	0.33	0.4	0,00	

Notes:

a. Package limited.b. Surface Mounted on 1" x 1" FR4 board. c. t = 10 s.

d. Maximum under Steady State conditions is 40 °C/W.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	-					1	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V$ , $I_{D} = -250 \mu A$	- 40			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 40			
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	i <sub>D</sub> = - 250 μA		- 5.5		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 2	- 3	- 4	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zana Osta Malla da Ducia Osmanl		$V_{DS} = -40 \text{ V}, V_{GS} = 0 \text{ V}$	<sub>3</sub> = 0 V				
Zero Gate Voltage Drain Current	IDSS	$V_{DS}$ = - 40 V, $V_{GS}$ = 0 V, $T_{J}$ = 55 °C			- 10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$	- 120			Α	
Drain-Source On-State Resistance <sup>a</sup>	r <sub>DS(on)</sub>	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 20 A		0.0041		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 20 A		75		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			11300			
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = - 25 V, $V_{GS}$ = 0 V, f = 1 MHz		1510		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			1000			
Total Gate Charge	Qg			185	280		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ = - 20 V, $V_{GS}$ = - 10 V, $I_{D}$ = - 110 A		48		nC	
Gate-Drain Charge	Q <sub>gd</sub>			42			
Gate Resistance	R <sub>g</sub>	f = 1 MHz		4.0		Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			25	40		
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 20 V, $R_L$ = 0.18 $\Omega$		290	440		
Turn-Off Delay Time	t <sub>d(off)</sub>	$\text{I}_\text{D}\cong$ - 110 A, $\text{V}_\text{GEN}$ = - 10 V, $\text{R}_\text{g}$ = 1 $\Omega$		110	165	- ns	
Fall Time	t <sub>f</sub>			35	55		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	۱ <sub>S</sub>	T <sub>C</sub> = 25 °C			- 110	A	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 240	~	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = - 20 A		- 0.8	- 1.5	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			70	105	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 20 A, di/dt = 100 A/μs, T <sub>J</sub> = 25 °C		130	200	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$r_{\rm F} = 2000, 0000 = 100000000, r_{\rm J} = 2000$		37		ne	
Reverse Recovery Rise Time	t <sub>b</sub>			33		ns	

Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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- 55 °C

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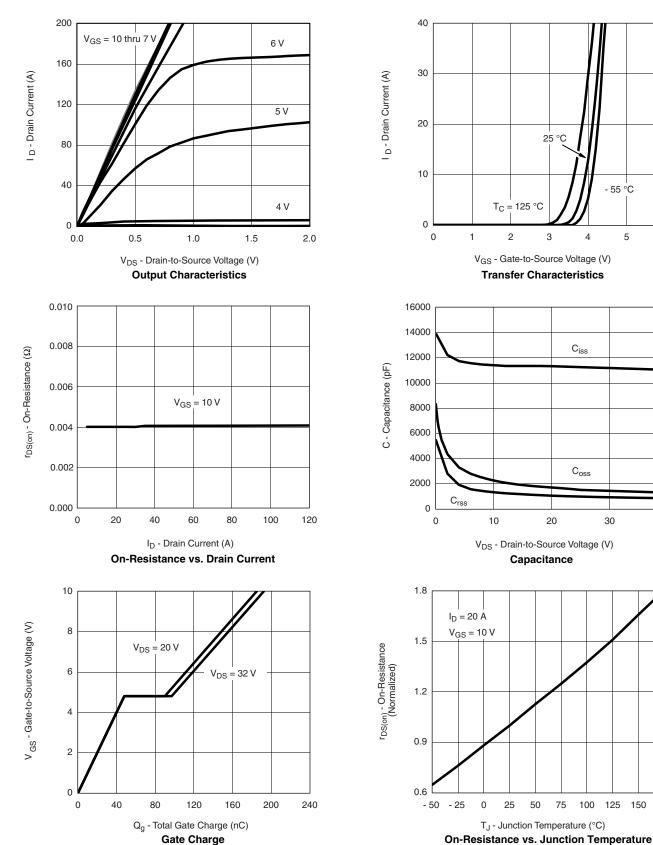
C<sub>iss</sub>

Coss

100 125

30

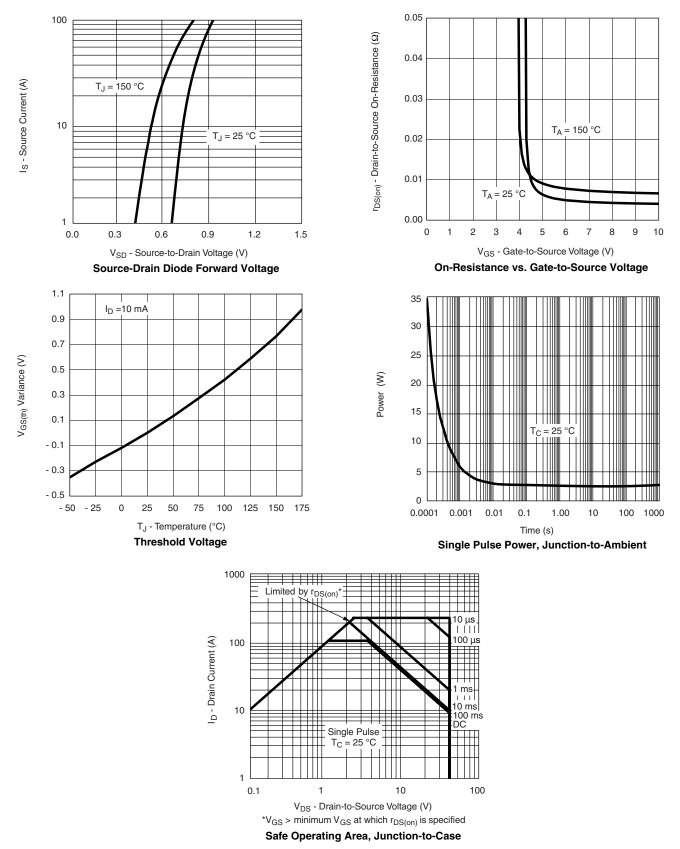
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#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

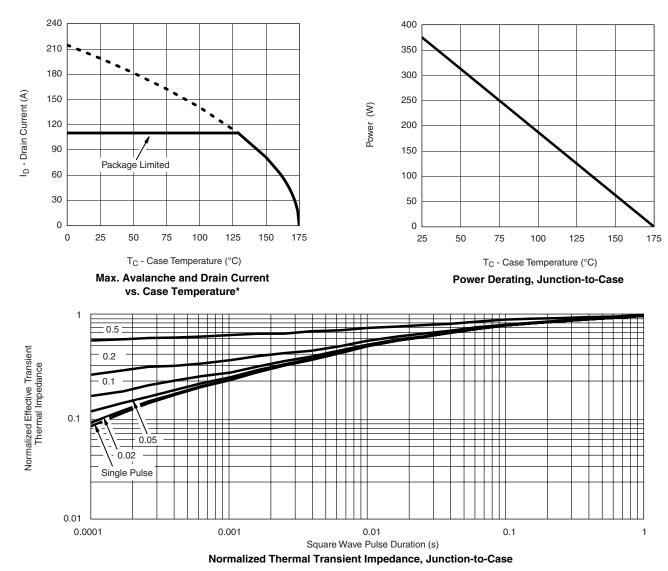
150 175





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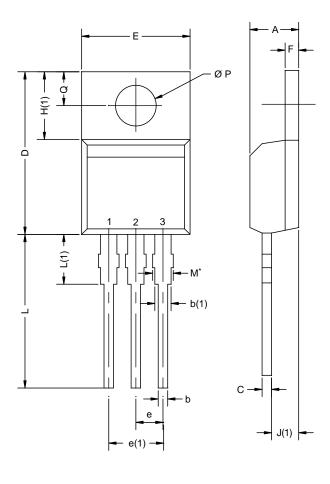


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



## **TO-220AB**



	MILLIN	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
Е	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12-0 DWG: 547	0208-Rev. N, 1	08-Oct-12		

#### Notes

 $^{\star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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